COPY SHEET 1

OF 1

Form PTO 1449		ATENT AND TRAC	OF COMMERCE	ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRAC	DEMARK OFFICE	244896US2CONT	10/717,644			
				APPLICANT				
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Kunio YONENO				
				FILING DATE		GROUP		
				November 21, 2003		2674		
U.S. PATENT DOCUMENTS								
EXAMINER		DOCUMENT	DATE	NAME	CLASS	SUB CLASS		LING DATE
INITIAL	AA	NUMBER 5,940,136	08/17/99	Hideki ABE, et al.	<del>                                     </del>	CLASS	ii / ii / iii/iii	
	AB	5,940,130	00/1//99	nideki ADE, et al.	<del> </del>			
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	AN	<u> </u>				-		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
	AO	6-046374	02/18/1994	JAPAN (submitting unedited computer-generated English translation only of previously submitted reference)		×		
	AP							
	AQ							
	AR							
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	AT							
	AU							
	AV		<u></u>					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY		· ···					
	AZ		· · · <u>——</u> · · · · · · · · · · · · · · · · · ·		Additional References sheet(s) attached			
Examiner					Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								